Abstracts

A High-Resolution Swept-Frequency Reflectometer

D.L. Hollway and P.I. Somlo. "A High-Resolution Swept-Frequency Reflectometer." 1969 Transactions on Microwave Theory and Techniques 17.4 (Apr. 1969 [T-MTT]): 185-188.

A simple swept-frequency reflectometer is described that is capable of measuring reflection coefficients as low as 0.001 and is particularly suitable for precise impedance matching. With the exception of a length of accurate plain waveguide, used as a standard, the instrument contains no critical components and requires no tuning adjustments. The reflection coefficient is displayed on an oscilloscope or X-Y recorder on an almost linear scale that is only slightly affected by departures from square-law detection.

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